### **TELECOMMUNICATION SYSTEM SECONDARY PROTECTION**

 Ion-Implanted Breakdown Region Precise and Stable Voltage Low Voltage Overshoot under Surge

DEVICE	V <sub>(Z)</sub>	V <sub>(BO)</sub>
DEVICE	v	v
'4290	200	290

- Planar Passivated Junctions
  Low Off-State Current < 10 μA</li>
- Rated for International Surge Wave Shapes

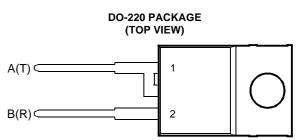
WAVE SHAPE	STANDARD	I <sub>TSP</sub> A
8/20 µs	ANSI C62.41	150
10/160 µs	FCC Part 68	60
10/560 µs	FCC Part 68	45
0.2/310 µs	RLM 88	38
	FTZ R12	50
10/700 µs	VDE 0433	50
	CCITT IX K17/K20	50
10/1000 µs	REA PE-60	35

### • UL Recognized, E132482

### description

The TISP4290 is designed specifically for telephone equipment protection against lightning and transients induced by a.c. power lines. These devices consist of a bidirectional suppressor element connecting the A and B terminals. They will suppress inter-wire voltage transients.

Transients are initially clipped by zener action until the voltage rises to the breakover level, which causes the device to crowbar. The high crowbar holding current prevents d.c. latchup as the transient subsides.



Pin 1 is in electrical contact with the mounting base.

MD4XAB

device symbol



These monolithic protection devices are fabricated in ion-implanted planar structures to ensure precise and matched breakover control and are virtually transparent to the system in normal operation.



# TISP4290 SYMMETRICAL TRANSIENT VOLTAGE SUPPRESSORS

APRIL 1987 - REVISED SEPTEMBER 1997

### absolute maximum ratings at 25°C case temperature (unless otherwise noted)

RATING	SYMBOL	VALUE	UNIT	
Non-repetitive peak on-state pulse current (see Notes 1, 2 and 3)				
8/20 μs (ANSI C62.41, open-circuit voltage wave shape 1.2/50 μs)		150		
10/160 μs (FCC Part 68, open-circuit voltage wave shape 10/160 μs)		60		
5/200 μs (VDE 0433, open-circuit voltage wave shape 2 kV, 10/700 μs)		50		
0.2/310 μs (RLM 88, open-circuit voltage wave shape 1.5 kV, 0.5/700 μs)	I <sub>TSP</sub>	38	А	
5/310 μs (CCITT IX K17/K20, open-circuit voltage wave shape 2 kV, 10/700 μs)	_	50		
5/310 μs (FTZ R12, open-circuit voltage wave shape 2 kV, 10/700 μs)		50		
10/560 μs (FCC Part 68, open-circuit voltage wave shape 10/560 μs)		45		
10/1000 μs (REA PE-60, open-circuit voltage wave shape 10/1000 μs)		35		
Non-repetitive peak on-state current, 50 Hz, 2.5 s (see Notes 1 and 2)	I <sub>TSM</sub>	10	A rms	
Initial rate of rise of on-state current, Linear current ramp, Maximum ramp value < 38 A	di <sub>T</sub> /dt	250	A/µs	
Junction temperature	TJ	150	°C	
Operating free - air temperature range		0 to 70	°C	
Storage temperature range	T <sub>stg</sub>	-40 to +150	°C	
Lead temperature 1.5 mm from case for 10 s	T <sub>lead</sub>	260	°C	

NOTES: 1. Above 70°C, derate linearly to zero at 150°C case temperature

2. This value applies when the initial case temperature is at (or below) 70°C. The surge may be repeated after the device has returned to thermal equilibrium.

3. Most PTT's quote an unloaded voltage waveform. In operation the TISP essentially shorts the generator output. The resulting loaded current waveform is specified.

# electrical characteristics, $T_J = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Vz	Reference zener	$I_7 = \pm 1 \text{mA}$	± 200			V
•∠	voltage		± 200			v
∝Vz	Temperature coefficient			0.1		%/°C
٧Z	of reference voltage			0.1		707 <b>O</b>
V <sub>(BO)</sub>	Breakover voltage	(see Notes 4 and 5)			± 290	V
I <sub>(BO)</sub>	Breakover current	(see Note 4)	± 0.15		± 0.6	Α
V <sub>TM</sub>	Peak on-state voltage	$I_T = \pm 5 A$ (see Notes 4 and 5)		± 1.9	± 3	V
Ι <sub>Η</sub>	Holding current	(see Note 4)	± 150			mA
dv/dt	Critical rate of rise of	(see Note 6)			± 5	kV/us
uv/ui	off-state voltage			<u> </u>	± J	κν/μ3
la la	Off-state leakage	$V_{D} = \pm 50 \text{ V}$			± 10	μA
Ι <sub>D</sub>	current	vD 30 v			÷ 10	μΛ
C <sub>off</sub>	Off-state capacitance	$V_D = 0$ f = 1 kHz		110	200	pF

NOTES: 4. These parameters must be measured using pulse techniques,  $t_w$  = 100  $\mu s,$  duty cycle  $\leq$  2%.

5. These parameters are measured with voltage sensing contacts seperate from the current carrying contacts located within 3.2 mm (0.125 inch) from the device body.

6. Linear rate of rise, maximum voltage limited to 80 % Vz (minimum).

### thermal characteristics

PARAMETER		TYP	MAX	UNIT
R <sub>0JA</sub> Junction to free air thermal resistance			62.5	°C/W



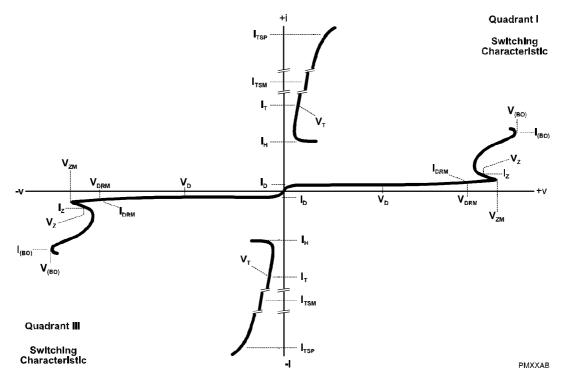
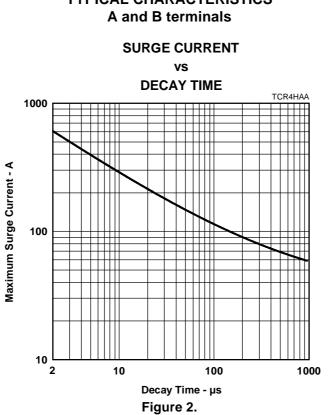


Figure 1. VOLTAGE-CURRENT CHARACTERISTIC FOR TERMINALS A AND B





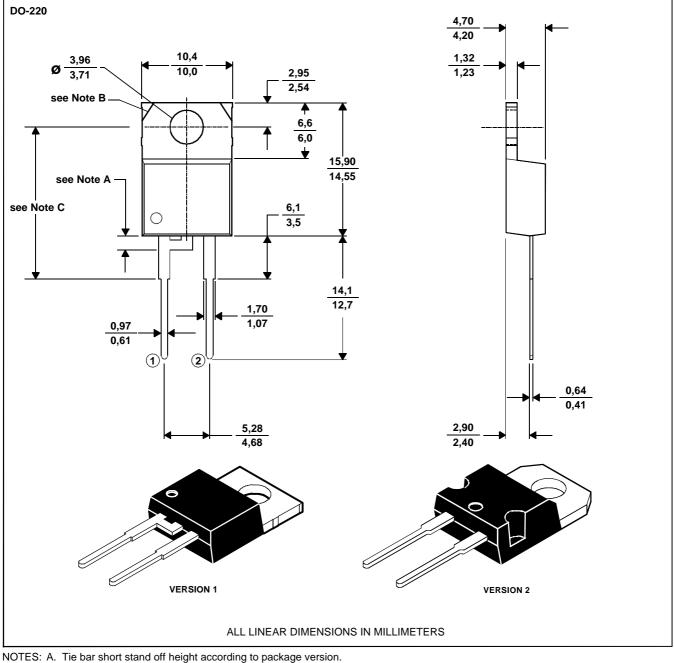
# **TYPICAL CHARACTERISTICS**

### **MECHANICAL DATA**

### DO-220

### 2-pin plastic flange-mount package

This single-in-line package consists of a circuit mounted on a lead frame and encapsulated within a plastic compound. The compound will withstand soldering temperature with no deformation, and circuit performance characteristics will remain stable when operated in high humidity conditions. Leads require no additional cleaning or processing when used in soldered assembly.



Version 1, pin 1 is in electrical contact with the mounting tab via tie bar short - stand off height : 2,0 mm maximum.

Version 2, pin 1 is in electrical contact with the mounting tab (no external tie bar short).

B. Mounting tab corner profile according to package version.

- C. Typical fixing hole centre stand off height according to package version.
- Version 1, 18,0 mm. Version 2, 17,6 mm.





### **IMPORTANT NOTICE**

Power Innovations Limited (PI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to verify, before placing orders, that the information being relied on is current.

PI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with PI's standard warranty. Testing and other quality control techniques are utilized to the extent PI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except as mandated by government requirements.

PI accepts no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor is any license, either express or implied, granted under any patent right, copyright, design right, or other intellectual property right of PI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.

PI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS.

Copyright © 1997, Power Innovations Limited